



NEPP Processor Enclave: Post COVID Update

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Acronyms

- Advanced Micro Devices (AMD)
- Application Specific Integrated Circuit (ASIC)
- Artificial Intelligence (AI)
- Advanced RISC Machine (ARM)
- Automated Test Equipment (ATE)
- Board Level Adapter Plate (BLAP)
- Body of Knowledge (BOK)
- Complementary metal oxide semiconductor (CMOS)
- Commercial off-the-shelf (COTS)
- Compute Unified Device Architecture (CUDA)
- Dual Data Rate (DDR)
- Device under test (DUT)
- Electrical, Electronic and Electromechanical (EEE)
- Field programmable gate array (FPGA)
- Fin Field-effect transistor (FinFET)
- General Purpose Input / Output (GPIO)
- Graphics Processing Unit (GPU)
- High Performance Computing (HPC)
- Input / Output (IO)
- Intellectual Property (IP)
- Linear energy transfer (LET)
- Key Process Indicators (KPI)
- LINear equations software PACKAge (LinPack)
- Machine Learning (ML)
- Mean time to failure (MTTF)
- Multi-Bit Upset (MBU)
- National Aeronautic and Space Administration (NASA)
- NASA Electronic Parts and Packaging (NEPP)
- Numerical Python (NumPy)
- Open Compute Language (OpenCL)
- Open Graphics Language (OpenGL)
- Operating System (OS)
- Printed Circuit Board Assembly (PCBA)
- Procurement Request (PR)
- RApid Machine-IEarned Triage (RAMJET)
- Single-Bit Upset (SBU)
- Scientific Python (SciPy)
- Single-Event Effect (SEE)
- Single-Event Functional Interrupt (SEFI)
- Single-Event Upset (SEU)
- Single-Event Upset Cross-Section (σ_{SEU})
- Simultaneous Localization And Mapping (SLAM)
- System on Chip (SOC)
- System on Module (SOM)
- Transiting Exoplanet Survey Satellite (TESS)
- Technical Operation Report (TOR)



FY20-22 Hardware Roadmap

- FPGA Co-Processor Devices
 - Xilinx Zynq
 - Xilinx MPSOC
 - Xilinx Versal
- Low Power Microprocessors
 - AMD Ryzen 3 1200, 2200G
 - Intel Core i7 6500U (Purism Librem)
 - Intel Core i7 10710U Comet Lake (Purism Librem, expected Q3)
- SOCs with GPUs
 - AMD Ryzen Low Power R1102G, v1202B, R1305G, R1606
 - NVIDIA Jetson TX2, TX2i, Nano
 - NVIDIA Xavier AGX, NX, AGXi (expected Q3)
- Low Power SOCs
 - NXP i.MX 8 QuadMax, Pro
 - Edgeless EAI Series
 - Allwinner F1C200s
 - Samsung Exynos
 - Qualcomm Snapdragon
 - RISC-V (several candidates tracked)
 - Raspberry Pis (*Guertin JPL)
- Neural Network Devices
 - Google TPU (rev 1, rev 3)
 - Intel (Movidius/Nervana/Loihi)
 - RockChip Rk1808, Rk3399Pro
 - Nepes NM500
 - ARM Ethos-U55, U65 (NXP i.MX 8M Plus kit)
 - Sipeed Maix
 - Amlogic S905X3 (ODROID-C4 kit)
 - Gyrfalcon Lightspeur AI
 - Xilinx Alveo
 - Texas Instruments Sitara AM57x
 - Kneron KL520, KL720
 - SimpleMachines
- Graphics Processing Units (discrete)
 - AMD Radeon e9173
 - NVIDIA GTX 1050

Red font devices were prepared for SEE testing during COVID in FY20 and FY21.
 Green font indicates procurement in FY21.
 Blue font indicates procurement in FY22.



FY22: Processor Enclave Testing

Description:

- This is a task over all device topologies and processes
- The intent is to determine inherent radiation tolerance and sensitivities
- Identify challenges for future radiation hardening efforts
- Investigate new failure modes and effects
- Testing includes total dose, single event and reliability. Test vehicles will include CPU, SOC and GPU devices from NVIDIA and other vendors as available
 - Compare to previous generations
 - Investigate failure modes/compensation for increased power consumption

FY22 Plans:

- Finish development of universal test suite which includes math (FFT, LinPack, Pi), output buffer (colors), memory hierarchy and neural networks
- Probable test structures for SEE and TID are COTS from:
 - NVIDIA (<16nm)
 - AMD (<14nm)
 - Intel (~10nm)
 - Samsung (<14nm)
 - Others (<45nm)
- Tests: characterization pre-rad, during and post-rad

Schedule:

Microelectronics T&E	FY 21											
	S	O	N	D	J	F	M	A	M	J	J	A
On-going discussions for test samples	█	█	█	█	█	█	█	█	█	█	█	█
Design & Fabrication of Cold Plate Parts	█	█	█	█	█	█	█	█	█	█	█	█
SEE and TID testing	█	█	█	█	█	█	█	█	█	█	█	█
Analysis and Comparison	█	█	◇	█	█	◇	█	█	◇	█	█	◇

Lead Center/PI: GSFC/SSAI/Wyrwas
Co-Is: Steve Guertin + Scott Stansberry

Deliverables:

- Test reports and quarterly reports
- Expected submissions for publications
- Cold plate and board level adapters

NASA and Non-NASA Organizations/Procurements:

- Source procurements:
 - Proton (MGH, Provision)
 - Heavy Ions (LBNL, TAMU)
 - TID (GSFC)
 - Laser (NRL)



FY22: AI & Machine Learning Devices

Description:

- This is a task over all device topologies and processes
- The intent is to determine inherent radiation tolerance and sensitivities and provide a baseline of current market offerings
- Identify challenges for future radiation hardening efforts
- Investigate new failure modes and effects
- Testing includes total dose, single event and reliability. Test vehicles will include 'simple interface' devices with USB or similar connectivity.
 - Identifies viable suppliers and provide insight into product obsolescence roadmaps
 - Investigate failure modes and mitigation strategies for increased power consumption and latch up events

FY22 Plans:

- Deploy AI and Machine Learning test suite developed in FY20, making refinements where necessary
- Probable test structures for SEE:
 - USB and other peripheral bus devices
 - 45nm down to 7nm
- Tests:
 - Electrical characterization pre-rad, during and post-rad
 - Functional testing with AI/ML accuracy and other KPI

Schedule:

Microelectronics T&E	FY 21											
	S	O	N	D	J	F	M	A	M	J	J	A
On-going discussions for test samples	█	█	█	█	█	█	█	█	█	█	█	█
Science community collaborations	█	█	█	█	█	█	█	█	█	█	█	█
SEE and TID testing	█	█	█	█	█	█	█	█	█	█	█	█
Analysis and Comparison	█	█	◇	█	█	◇	█	█	◇	█	█	◇

Lead Center/PI: GSFC/SSAI/Wyrwas
Co-Is: Alyson Topper + Scott Stansberry

Deliverables:

- Test reports and quarterly reports
- Expected submissions for publications
- Additional cold plate and board level adapters

NASA and Non-NASA Organizations/Procurements:

- Source procurements:
 - Proton (MGH, Provision)
 - Heavy Ions (LBNL, TAMU)
 - TID (GSFC)
 - Laser (NRL)



Evaluation Timeline

***Radiation Testing (RT)**

***Cold Block (CB) Adapter Development**

***Test Feasibility Evaluation (FE)**

***Continuation** ← or →

***Termination** ● or ●

Microprocessors

- ≤14nm++ Intel (Intel)
- ≤10nm AMD (Global)

Microprocessors with embedded GPUs

- 14nm++ Intel (Intel)
- ≤ 10nm AMD (Global)
- 10nm Qualcomm 835 (Samsung)

GPUs

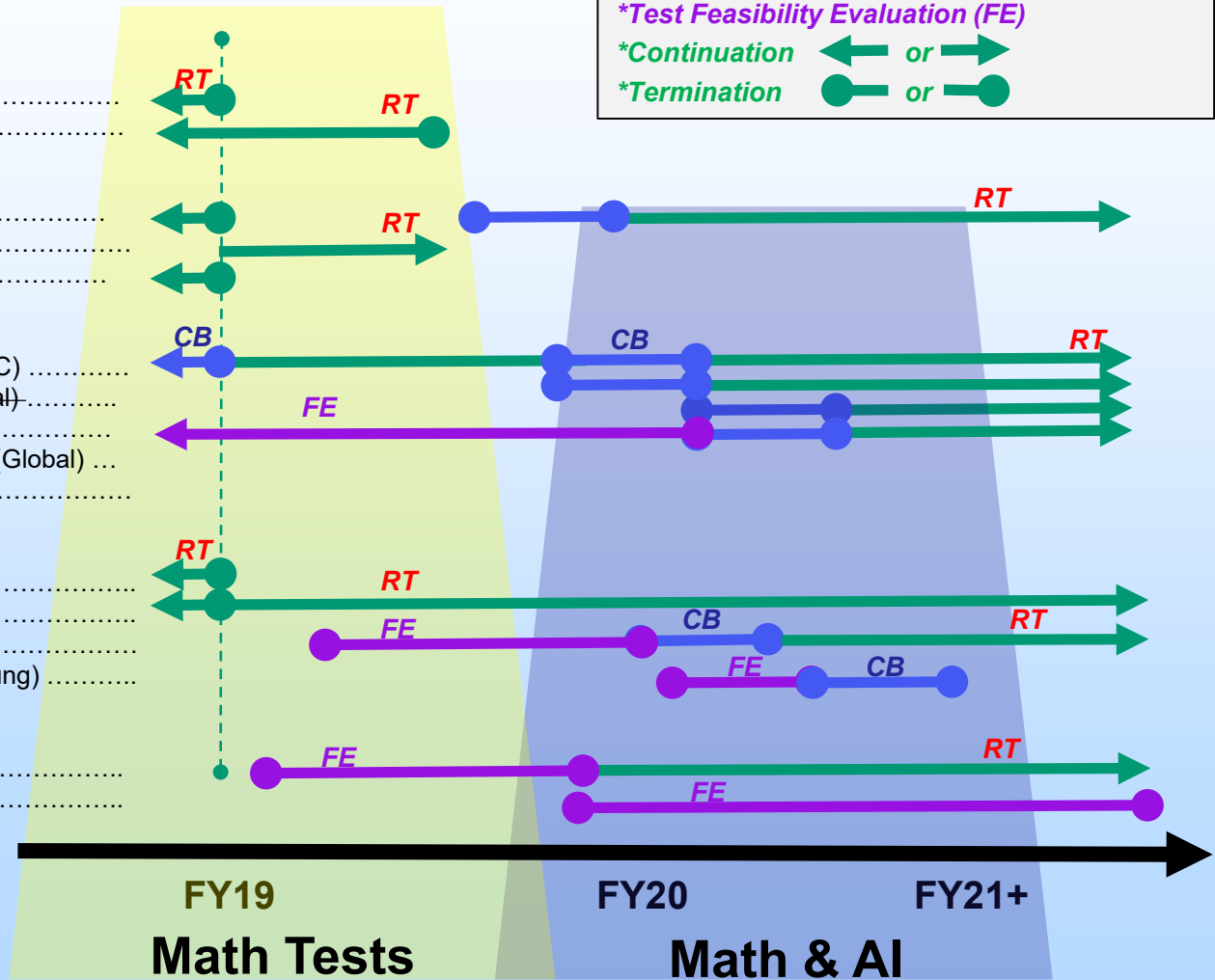
- 14/16nm NVIDIA GTX 1050/1080 (TSMC)
- 14nm AMD Radeon RX580/Vega (Global)
- 14nm Intel Discrete GPU (Intel)
- 14nm Low Power, AMD Radeon e917x (Global) ...
- 12nm NVIDIA RTX 2080 (TSMC)

System on Chip

- 20nm NVIDIA Tegra X1 (TSMC)
- 16nm NVIDIA Tegra X2 (TSMC)
- 12nm NVIDIA Tegra Xavier (TSMC)
- ≤ 10nm Qualcomm Snapdragon (Samsung)

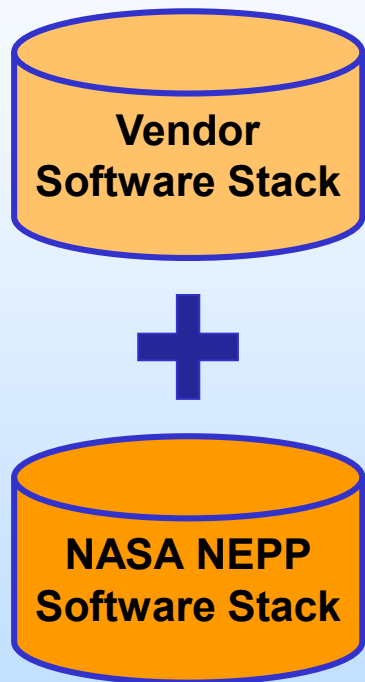
Neural Network Devices

- Google TPU.....
- Many, many others.....





NEPP Software - Recap



- Software stack from vendor is comprised of Linux, PCBA carrier board drivers and hardware initializers, and some health prognostic tools
- Software stack from NASA NEPP is comprised of
 - 2x Mathematics tests (CUDA, OpenCL)
 - 1x Graphics buffer test (OpenGL)
 - 1x Linear Algebra test (Linpak)
 - 4x Artificial Intelligence tests (Python including SciPy and NumPy, Keras and TensorFlow 2.0)
- Android OS applications for Math and Graphics are in development too. The TensorFlow Lite one is complete.



Microsoft Teams Channel - Recap

- **“NEPP – Processor Enclave”**
 - NASA users can join with the team code: 1a2iu5y
- **Contains many wiki and files which cover:**
 - Set up, wiring and programming instructions for various devices and single board computers
 - Troubleshooting
- **We discuss SOTA device landscapes in the chat**
 - New COTS devices and development kits
 - New architectures and technology demos
 - Press release announcements and solicitations



GitLab

- **NEPP and NEPP collaborators – authors credited**
- **Shared within NASA network**
- **So far > 40GB of content has been uploaded**
 - **CPU, GPU and AI Test Suites**
 - **Benchtop instrumentation**
 - **Build Guides**
 - **Distributable Reports**
- **The goal is to provide a singular source of standardized testing programs, scripts and applications for benchmarking and radiation testing GPUs, Microprocessors and AI devices**



<https://aetd-git.gsfc.nasa.gov/edward.j.wyrwas/nepp-processor-enclave>



Bi-Weekly Processor Enclave Telecon

- **Space community, OEMs and component manufacturers**
- **Contact Steve Guertin (JPL) to join the mailing list with the call's dial-in and Webex information**

Steve Guertin

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Partners

- **NASA JPL / NEPP west coast (Steve Guertin, Andrew Daniel)**
- **Sandia (David Lee)**
- **Indiana University (Hacking 4 Defense '21)**
- **NASA MATISSE / CU μ LUS (Rich Barry)**
- **NASA JSC xEMU teams**
- **DAVINCI+ / CUVIS Instrument**
- **Space Force (Tyler Lovelly, Jesse Mee)**
- **Troxel Aerospace**
- **JHU APL (Chris Heistand, Sarah Katz)**
- **Microprocessor Working Group**
- **NASA Additive Manufacturing Working Group**
- **ASME Additive Manufacturing Working Group on Non-Metallic Polymers**



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